Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,466	LEE ET AL.	
Examiner	Art Unit	
Nyeemah Grazier	1626	

SEARCHED			
Class	Subclass	Date	Examiner
544	153, 170	6/30/2005	NG
		·	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC		·)
	DATE	EXMR
Classification	6/30/2005	NG
STN (Structure + Process)	6/29/2005	NG
Inventor Name	6/30/2005	NG
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